

IEC QUALITY ASSESSMENT SYSTEM (IECQ) covering Electronic Components, Assemblies, Related Materials and Processes

SSEMDIIES, RELATED MATERIALS AND PROCESSE For rules and details of the IECQ visit <u>www.iecq.org</u>

Schedule of Scope to Certificate of Approval

Independent Testing Laboratory

IECQ Certificate No.: IECQ-L ULTW 16.0003-07

CB Certificate No.: 50600097 ITL

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Appendix-1 (50600097 ITL) Schedule of Scope to Certificate of Approval

Description test	Standard
Scanning Electron Microscope (SEM)	T-SEM-3
Transmission Electron Microscope - Electron Energy Loss Spectroscopy (TEM-EELS)	T-TEM-3
Focused Ion Beam microscope (FIB)	T-FIB-3
Emission Microscopy-InGaAs (EMMI-InGaAs)	T-EFA-3
Optical Microscope (OM)	T-OMI-3
IC Layout Imaging	T-OMI-3
Decapsulation	T-LAB-3
Chemical	T-LAB-3
Delayer	T-LAB-3

michael Chou Technical Reviewer of DQS: Date: 7/15/2022

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